

3-A Peak, High Voltage, High Frequency High-Side and Low-Side Driver

1. Description

The MD18201A high-frequency gate driver includes a 120-V bootstrap diode, and is designed to drive both high-side and low-side N-Channel MOSFETs with maximum control flexibility of independent inputs.

The inputs can handle -10V to 20V DC, which increases robustness against ringing from gate transformer and/or parasitic inductance of long routing traces.

High side driver is designed to be protected from negative spikes at HS pin as low as -18V, caused by parasitic inductance and stray capacitance.

15ns rising and 14ns falling propagation delay allows the systems operating at high frequency with less delay matching variations.

The MD18201A is offered in SOP-8 and ESOP-8 packages

2. Typical Applications

- Power Supplies for Telecom, Datacom, and 48V to 72V Battery Powered Systems
- Half-Bridge Applications and Full-Bridge Converters
- Push-Pull Converters
- High Voltage Synchronous Buck Converters
- Two-Switch Forward Converters
- Active Clamp Forward Converters
- Class-D Audio Amplifiers

3. Features

- Drives Both High-Side and Low Side N-Channel MOSFETs with Independent Inputs
- Operating Switching Frequency up to 1MHz
- Bootstrap Supply Voltage up to 120V DC
- 3-A Source and Sink Output Peak Currents
- 6.5-ns Rise and 5.3-ns Fall Time with 1000-pF Load
- Input Pins Can Tolerate -10V to +20V, and are Independent of Supply Voltage Range
- TTL Compatible Inputs
- 8V to 17V VDD Operating Range, 20V ABS MAX
- Fast Propagation Delay Times
- Excellent Propagation Delay Matching (1ns Typical)
- Symmetrical Undervoltage Lockout for High-Side and Low-Side Driver
- Available in SOP-8 and ESOP-8 packages
- Specified from -40°C to 140°C

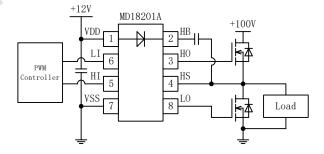


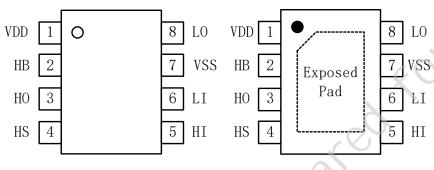
Figure 1. Typical Application Diagram



4. Order Information

Order Code	Package	Pins	SPQ (pcs)	
MD18201ATAA	SOP-8	8	4000	(
MD18201ATAD	ESOP-8	8	4000	
5. Package Re	ference and P	in Functions	Š	Oli
VDI	\exists	8 LO VDD	8 LO	

5. Package Reference and Pin Functions



SOP-8 (top view)

ESOP-8 (top view)

Pin Number	Name	Description
1	VDD	Positive gate drive supply. Locally decouple to VSS using low ESR/ESL capacitor located as close to the device as possible
2	НВ	High-side bootstrap supply. Connect to the positive terminal of bootstrap capacitor that should be placed as close to the device as possible.
3	НО	High-side gate driver output. Connect to the gate of high-side MOSFET with a short, low inductance path
4	HS	High-side source connection. Connect to the negative terminal of bootstrap capacitor and the source of the high-side N-Channel MOSFET
5	Н	High-side input
6		Low-side input
7	VSS	Negative supply for the device that is generally grounded. All signals of the device are referenced to this ground
8	LO	Low-side gate driver output. Connect to the gate of low-side MOSFET with a short, low inductance path



6. Absolute Maximum Ratings (1)

VDD, HB-HS	
LI, HI	
HS-VSS DC	
Repetitive pulse (2)	
LO DC	0.2\/ to \/DD + 0.2\/
Repetitive pulse (2)	_2V to VDD+0.3V
Repetitive pulse (3)	
HO-HS DC	0.01/4-1/00.00/
Repetitive pulse (2)	_2V to VDD+0.3V
Repetitive pulse (3)	
HB-VSS	
Power Dissipation at TA = +25°C (4)	
Junction Temperature	-40°C to 150°C
Lead Temperature (Solder)	
Storage Temperature	

7. Recommend Operation Conditions (5)

VDD		8V to 17V
HS-VSS DC		-1V to 105V
Repetitive pulse (2)		
HB-VSS		HS+8V to HS+17V
	<u>O`</u>	VDD-1V to 115V
HS Slew Rate		<50V/ns
Maximum Junction Temp. (T _J)		
	r - r	

8 Thermal Resistance (6)

 θ_{JA} θ_{JC}

SOP-8		106.0	52.0°C/W
FSOP-8	. 0	40.0	48 0°C/W

Notes

- (1) Exceeding these ratings may cause permanent damage to the device
- (2) Repetitive pulse ≤100ns. Verified at bench characterization
- (3) Repetitive pulse ≤30ns. Verified at bench characterization
- (4) The maximum allowable power dissipation is a function of the maximum junction temperature $T_J(MAX)$, the junction-to-ambient thermal resistance θ_{JA} , and the ambient temperature T_A . The maximum allowable continuous power dissipation at any ambient temperature is calculated by $P_D(MAX)=(T_J(MAX)-T_A)/\theta_{JA}$. Exceeding the maximum allowable power dissipation will cause excessive die temperature.
- (5) The device is not guaranteed to function outside of its operating conditions.
- (6) Measured on JEDEC, 1S0P PCB.



9. Esd Ratings

		Value	Units
Electrostatic	Human body model (HBM), per ANSI/ESDA/JEDEC JS-001, all pins (1)	±2000	V
discharge V _{ESD}	Charged device model (CDM), per JEDEC specification JESD22-C101, all pins (2)	±2000	v ×

Notes:

- (1) JEDEC document JEP155 states that 500V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250V CDM allows safe manufacturing with a standard ESD control process.

10. Electrical Characteristics

VDD=V_{HB}=12V, V_{HS}=VSS=0V, T_A=T_J=-40°C to +140°C, unless otherwise noted.

Parameter	Symbol	Conditions	Min	Тур	Max	Units
SUPPLY CURRENTS		7				
VDD quiescent current	I _{VDD}	V(LI)=V(HI)=0V		0.2	0.4	mA
VDD operating current	I _{VDDO}	f=500kHz, C _{LOAD} =0		8.0	1.2	mA
HB total quiescent current	I _{HB}	V(LI)=V(HI)=0V		0.15	0.3	mA
HB total operating current	Інво	f=500kHz, C _{LOAD} =0		8.0	1.2	mA
HB to VSS quiescent current	I _{HBS}	V(HS)=V(HB)=105V		4	11	μΑ
HB to VSS operating current	I _{HBSO}	f=500kHz, C _{LOAD} =0		0.05		mA
Inputs						
Input voltage rising threshold	V _{ITH}			1.9	2.4	V
Input voltage falling threshold	VITL		8.0	1.5		V
Input voltage hysteresis	VITHYS			0.4		V
Input pulldown resistance	R _{IN}		100	230	350	kΩ
Undervoltage Lockout						
VDD rising threshold	V _{DDR}		6.4	7.1	7.8	V
VDD threshold hysteresis	V _{DDHYS}			0.49		V
HB rising threshold	V _{НВ}		6.0	6.8	7.5	V
HB threshold hysteresis	V _{HBHYS}			0.76		V
Bootstrap Diode						
Low-current forward voltage	V _{FL}	I _{VDD-HB} =100µА		0.62	0.84	V
High-current forward voltage	V _{FH}	I _{VDD-HB} =100mA		0.88	1.1	V
Dynamic resistance, ΔV _F /ΔI	R₀	I _{VDD-HB} =100mA and 80mA		0.74	1.12	Ω
Lo Gate Driver						
Low-level output voltage	V _{LOL}	I _{LO} =100mA		0.1	0.22	V
High-level output voltage	V _{LOH}	I _{LO} =-100mA, V _{LOH} =VDD-LO		0.13	0.27	V
Peak pull-up current		V _{LO} =0V		3		Α
Peak pull-down current		V _{LO} =12V		3		Α
Ho Gate Driver						



V _{HOL}	I _{HO} =100mA		0.1	0.22	V
V _{нон}	Iно=-100mA, Vнон=НВ-НО		0.13	0.27	V
	V _{HO} =0V		3		Α
	V _{HO} =12V		3		Α
T _{DLR}	LI rising to LO rising		15	30	ns
T _{DHR}	HI rising to HO rising		15	30	ns
T_DLF	LI falling to LO falling		14	30	ns
T _{DHF}	HI falling to HO falling		14	30	ns
T _{MON}			1	6	ns
T _{MOFF}			1	6	ns
			X.		
	C _{LOAD} =1nF		6.5		ns
	C _{LOAD} =1nF		5.3		ns
	C _{LOAD} =100nF	(0)	0.28	0.52	us
	C _{LOAD} =100nF		0.25	0.51	us
	10			10	nc
				10	ns
	I ₂ -20mΔ I ₂ -200mΔ		90		ns
	ווי–בטוות, וגי–בטטוות		30		115
	VHOH TDLR TDHR TDLF TDHF	VHOH IHO=-100mA, VHOH=HB-HO VHO=0V VHO=12V TDLR LI rising to LO rising TDHR HI rising to HO rising TDHF LI falling to LO falling TDHF HI falling to HO falling TMON TMOFF CLOAD=1nF CLOAD=100nF	VHOH IHO=-100mA, VHOH=HB-HO VHO=0V VHO=12V TDLR LI rising to LO rising TDHR HI rising to HO rising TDHF LI falling to LO falling TDHF HI falling to HO falling TMON TMON TMOFF CLOAD=1nF CLOAD=100nF CLOAD=100nF	VHOH IHO=-100mA, VHOH=HB-HO 0.13 VHO=0V 3 VHO=12V 3 TDLR LI rising to LO rising 15 TDHR HI rising to HO rising 15 TDLF LI falling to LO falling 14 TDHF HI falling to HO falling 14 TMON 1 1 TMOFF 1 1 CLOAD=1nF 5.3 6.5 CLOAD=100nF 0.28 CLOAD=100nF 0.25	VHOH IHO=-100mA, VHOH=HB-HO 0.13 0.27 VHO=0V 3 3 VHO=12V 3 3 TDLR LI rising to LO rising 15 30 TDHR HI rising to HO rising 15 30 TDLF LI falling to LO falling 14 30 TMF HI falling to HO falling 14 30 TMON 1 6 6 TMOFF 1 6 6 CLOAD=1nF 5.3 6 CLOAD=100nF 0.28 0.52 CLOAD=100nF 0.25 0.51

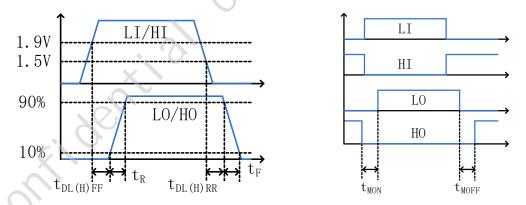


Figure 2. Timing Diagram



11. Typical Characteristics

Temp=25°C,VDD=HB=12V, C_{L HO}= C_{L LO}=0nF

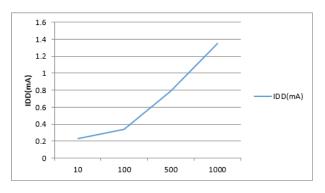


Figure 3. IDD Operating Current vs Frequency

Temp=25°C, VDD=HB=12V, C_{L_HO}= C_{L_LO}=0nF

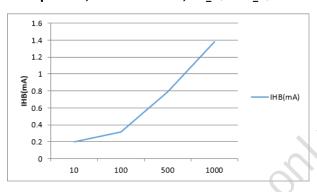


Figure 5. IHB Operating Current vs Frequency

Temp=25°C,C_{L_HO}= C_{L_LO}=0nF

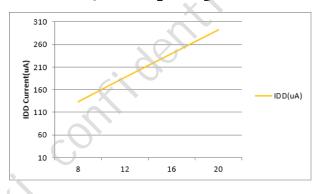


Figure 7. IDD Quiescent Current vs Supply Voltage

Frequency=100kHz, VDD=HB=12V, C_{L_HO} = C_{L_LO} =0nF

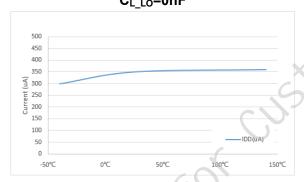


Figure 4. IDD Operating Current vs
Temperature

Frequency=100kHz, VDD=HB=12V, C_{L_HO}=

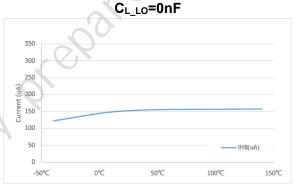


Figure 6. IHB Operating Current vs Temperature VDD=12V, $C_{L\ HO}$ = $C_{L\ LO}$ =0nF

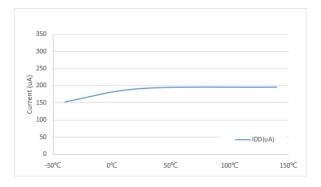


Figure 8. IDD Quiescent Current vs
Temperature



Temp=25°C,C_{L_HO}= C_{L_LO}=0nF

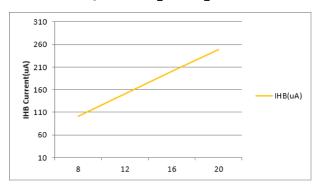


Figure 9. IHB Quiescent Current vs Supply
Voltage
Temp=25°C

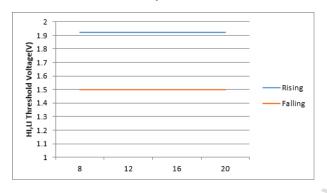
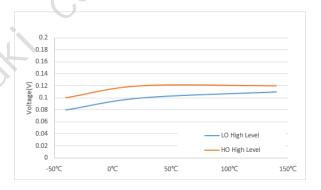


Figure 11. Input Threshold vs Supply Voltage VDD=12V



Figure 13. VDD threshold vs Temperature VDD=12V



VHB=12V,C_{L_HO}= C_{L_LO}=0nF

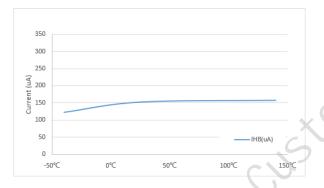


Figure 10. IHB Quiescent Current vs
Temperature
VDD=12V



Figure 12. Input Threshold vs Temperature VDD=12V

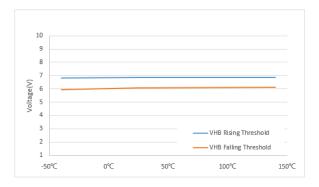
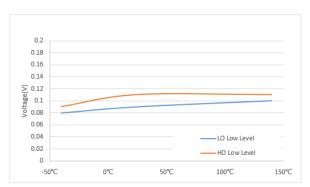


Figure 14. VHB threshold vs Temperature VDD=12V





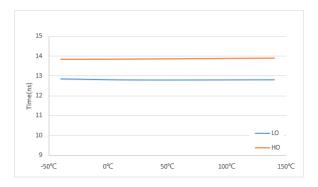


Figure 17. Turn Off Propagation Delay vs
Temperature

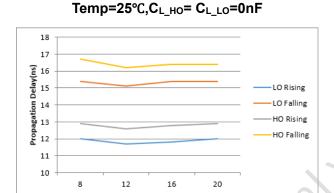


Figure 19. Propagation Delay vs Supply Voltage

 $VDD=12V,C_{L_HO}=C_{L_LO}=1nF$



Figure 21. Falling Time vs Temperature

Figure 16. Low Level Output Voltage vs

Temperature

VDD=12V,C_{L_HO}= C_{L_LO}=0nF

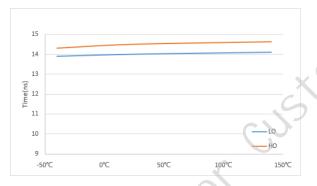
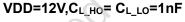


Figure 18. Turn On Propagation Delay vs
Temperature



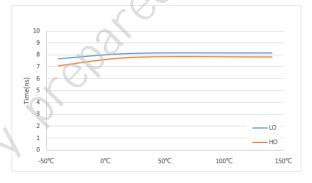


Figure 20. Rising Time vs Temperature

VDD=12V

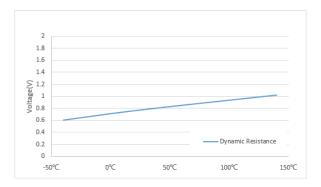


Figure 22. Dynamic resistance vs Temperature



12. Block Diagram

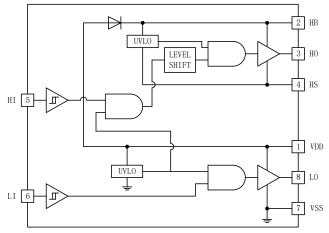


Figure 23. Functional Block Diagram

13. Operation

13.1 Overview

MD18201A is high-side and low-side driver which is designed to drive N-Channel MOSFETs in a half-bridge, full-bridge, synchronous-buck, synchronous-boost, push-pull, two-switch forward and active clamp forward converters.

The high-side and low-side each have independent inputs which allow maximum flexibility of input control signals in the application. The boot diode for the high-side driver bias supply is internal to the MD18201A.

13.2 Functional Modes

MD18201A operates in normal mode and UVLO mode. In the normal mode, the output state is dependent on states of the input pins. See as below:

HI PIN	LI PIN	HO PIN	LO PIN
XL	L	L	L
Н	L	Н	L
L	Н	L	Н
Н	Н	Н	Н

Notes:

- (1) HO is measured with respect to HS
- (2) LO is measured with respect to VSS

13.3 Input Stages

The input stages provide the interface to the PWM out signals and both input pins are independent. The input is compatible on TTL input-threshold logic that is independent of the VDD supply voltage. There is a pulldown resistance between LI(HI) and VSS (ground), and the resistance is used to make sure 'Low' logic when the VDD start to rise.

With typical high threshold and typical low threshold, MD18201A is conveniently controlled by 3.3V and 5V PWM controller devices.

13.4 Output Stages



The output stages are the interface to the power MOSFETs. Low resistance and high peak current capability of both outputs allow for efficient switching of the power MOSFETs. The low side output stage is referenced from VDD to VSS and the high side is referenced from HB to HS.

MD18201A provides excellent output negative voltage handling capability, thanks to its high peak current driving capability and 2kV HBM and 2kV CDM ESD performance.

13.5 Boot Diode

The boot diode is connected VDD pin to HB pin and used to charge the boot capacitor connected HB pin to HS pin. When HS pin transitions to ground, the current of VDD charge the boot capacitor until HS rising. The boot diode provides fast recovery time, low equivalent resistance and voltage rating to allow for reliable operation.

13.6 Undervoltage Lockout (UVLO)

The supplies for the high-side (HB to HS) and low-side (VDD to VSS) are monitored. When the voltage of VDD is below the specified threshold, the VDD UVLO disables low-side driver and send the signal by level shift to disable high-side driver. When the voltage of HB to HS is below the specified threshold, the HB UVLO disables only the high-side driver.

13.7 Level Shift

The level shift circuit is the interface from the high-side input to the high-side driver stage which is referenced to the switch node (HS). The level shift allows control of the HO output referenced to the HS pin and provides excellent delay matching with the low-side driver.



14. Application and implementation

14.1 Typical Applications

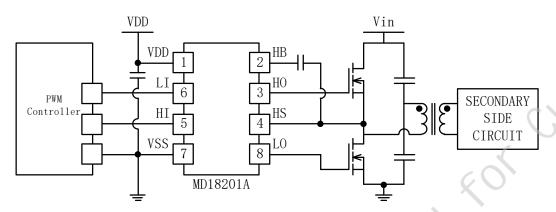


Figure 24. MD18201A Typical Application: Half Bridge

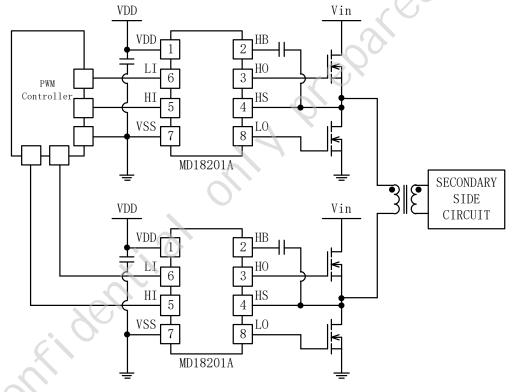


Figure 25. MD18201A Typical Application: Full Bridge



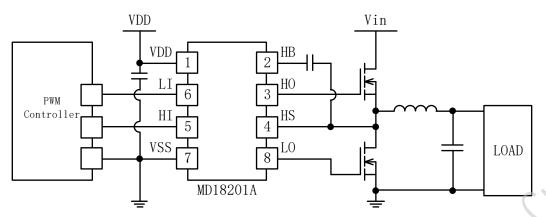


Figure 26. MD18201A Typical Application: Buck

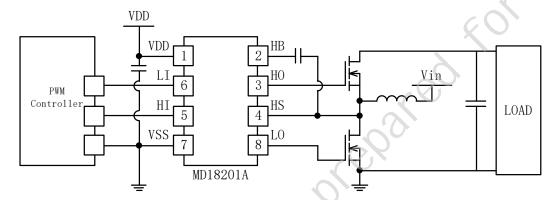


Figure 27. MD18201A Typical Application: Boost

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14.2 Design Procedure

14.2.1 Input Threshold Type

The MD18201A has an input maximum voltage range from -10V to 20V and can be directly interfaced to gate drive transformers. The MD18201A threshold voltage levels are independent of the VDD supply voltage, which allows compatibility with both logic-level input signals from MCU, DSP as well as analog controllers.

For system application, if there is long trace from PWM controller to driver, it is suggested that adding a RC filter close to HI pin and LI pin.

14.2.2 Supply Voltage

The supply voltage to be applied to the VDD pin of the driver should never exceed the absolute maximum rating. Higher voltage can reduce the conduction loss of MOSFET, and increase the switching loss.

The choice of HB-HS capacitor and VDD-VSS capacitor should be dependent on the switching frequency and C_{gs} of MOSFET. Use 100nF(50V) as HB-HS capacitor and 10uF(50V) paralleled with 100nF(50V) as VDD-VSS capacitor in the general. The function of paralleled capacitor is decoupling.

14.2.3 Peak Source and Sink Currents

The switching speed of the MOSFET during turning-on and turning-off should be as fast as possible in order to minimize switching power losses. The gate driver must be able to provide the required peak current for achieving the targeted switching speeds with the targeted power MOSFET.

For system application, adding a resistance (such as 1Ω or 2.2Ω) between gate of MOSFET and LO/HO can control the switching speed of the MOSFET. The faster turning-on speed, the higher the stress of Drain-Source of MOSFET, and the lower switching loss.

14.2.4 Propagation Delay

The propagation delay from the gate driver is dependent on the switching frequency and C_{gs} of MOSFET. The MD18201A ensures very little pulse distortion and allows operation at very high-frequency.

When using MD18201A as driver in Boost, Buck, synchronous rectification, PWM controller need to reserve enough deadtime between HI and LI.

14.2.5 Power Dissipation

Power dissipation of MD18201A has two portions as below

 $P_{DISS} = P_{DC} + P_{SW}$

The DC portion of the power dissipation is

 $P_{DC} = I_Q * VDD$

Where I_Q is the quiescent current for MD18201A. The quiescent current is the current consumed by the device to bias all internal circuits such as input stage, reference voltage, level shift circuits, UVLO circuit, and also any current associated with switching of internal devices when the driver output changes state.

The switching portion of the power dissipation include:

- (1) switching frequency
- (2) Q_G of the MOSFET
- (3) Supply voltage VDD

 $P_{SW} = Q_G * VDD * f_{SW}$



15. Layout

15.1 Layout Guidelines

To improve the switching characteristics and efficiency of a design, the following layout rules must be followed.

- (1) Locate the driver close to the MOSFETs.
- (2) Locate the VDD-VSS and HB-HS capacitors close to the driver.
- (3) Connect the VSS pin to thermal pad and use the thermal pad as GND. The GND trace from MD18201A does directly to the source of the low-side MOSFET, but not be in the high current path of MOSFET source current.
- (4) Use the same rules for HS as for GND for the high-side MOSFET.
- (5) For system using multiple drivers, the decoupling capacitors need to be located at VDD-VSS for each driver.
- (6) Avoid placing VDD, LI, HI trace close to LO, HS and HO signals or any other high dV/dT traces that can induce significant noise into the high impedance leads.
- (7) Use wide trace for LO and HO to decrease the influence of switching ringing made by parasitic inductance.
- (8) If the driver outputs or SW node must be routed from one layer to another, use at least two vias.
- (9) For GND, the number of vias must be a consideration of the thermal pad requirements as well as minimizing parasitic inductance.

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16. Tape And Reel Information

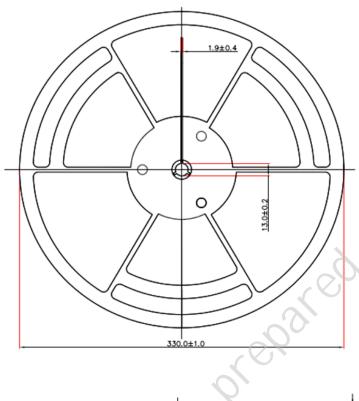
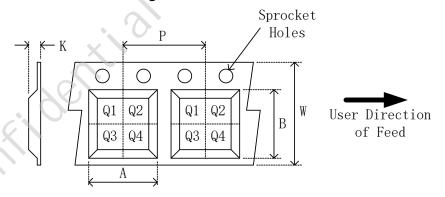




Figure 28. Reel Dimensions

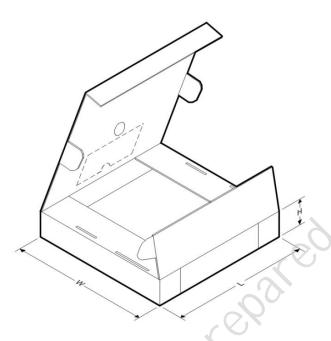


Device	Package	Pins	SPQ	Α	В	K	Р	W	Pin1
	Type		(pcs)	(mm)	(mm)	(mm)	(mm)	(mm)	Quadrant
MD18201ATAA	SOP-8	8	4000	6.5±0.1	5.4±0.1	2.0±0.1	8±0.1	12±0.1	Q1
MD18201ATAD	ESOP-8	8	4000	6.5±0.1	5.4±0.1	2.0±0.1	8±0.1	12±0.1	Q1

Figure 29. Tape Dimensions and Quadrant Assignments for PIN 1 Orientation in Tape



17. Tape And Reel Box Dimensions



Device	Package	Pins	SPQ	Length	Width	Height
	Type		(pcs)	(mm)	(mm)	(mm)
MD18201ATAA	SOP-8	8	8000	360	360	65
MD18201ATAD	ESOP-8	8	8000	360	360	65

Figure 30. Box Dimensions



18. Mechanical Data and Land Pattern Data

18.1 SOP-8

18.1.1 Mechanical Data

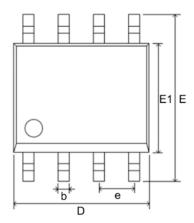


Figure 31. SOP-8 Top View

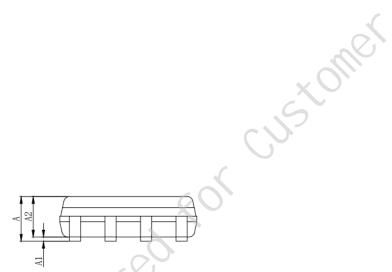


Figure 32. SOP-8 Side View

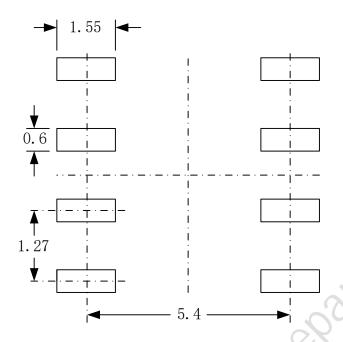


Figure 33. SOP-8 Side View

	CVMPOL	Millim	neter
	SYMBOL	MIN	MAX
	Α	1.3	1.75
	A1	0.05	0.25
	A2	1.25	1.65
	b	0.33	0.51
	С	0.2	0.25
	D	4.7	5.1
	Ш	5.8	6.2
	E1	3.8	4.0
	е	1.270((BSC)
	L	0.4	1.27
	θ	0°	8°
10			



18.1.2 Land Pattern Data



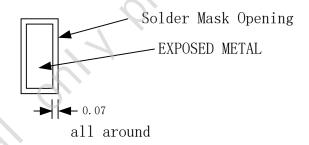
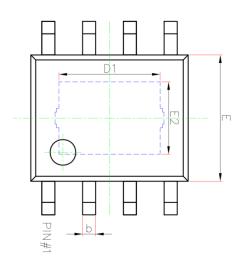


Figure 34. SOP-8 Land Pattern Data



18.2 ESOP-8

18.2.1 Mechanical Data



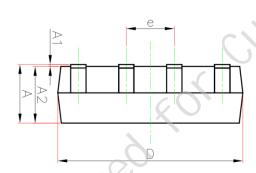


Figure 35. ESOP-8 Top View

Figure 36. ESOP-8 Side View

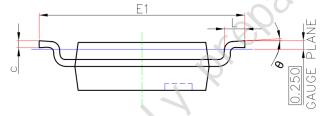


Figure 37. ESOP-8 Side View

	CVMPOL	Millimeter	
SYMBOL A A1 A2 b C D D1 E E1 E2 e L θ	MIN	NOM	
	Α	1.30	1.70
	A1	0.00	0.10
	A2	1.35	1.55
	b	0.33	0.51
	С	0.17	0.25
	D	4.70	5.10
	D1	3.05	3.25
	E	3.80	4.00
	E1	5.80	6.20
	E2	2.16	2.36
	е	1.27(BSC)	
	L	0.40	1.27
	θ	0°	8°



18.2.2 Land Pattern Data

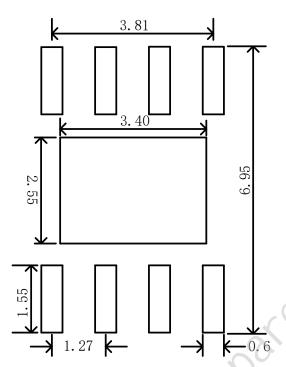


Figure 38. eSOP-8 Land Pattern Data

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